CAPACITORS, LEADLESS SURFACE MOUNTED,

TANTALUM, SOLID ELECTROLYTE,

ENCLOSED ANODE CONNECTION

ESCC Generic Specification No. 3012

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Pages 1 to 35

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ESA/SCC Generic Specification No. 3012

space components
coordination group

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		SCCG Chairman	ESA Director General or his Deputy
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DOCUMENTATION CHANGE NOTICE

Rev. Letter	Rev. Date	Reference	CHANGE Item	Approved DCR No.
		This Issue supersedes Issue 1 and incorporates all modifications defined in Revisions 'A', 'B' and 'C' to Issue 1 and the changes agreed in the following DCRs:-		
		Cover Page		None
		DCN		None
		Para. 9.3.2	: New first sentence added	221340
			: In the last sentence, "d.c." added before "leakage"	221340
		Para. 9.4.1.2	: "Current" added to Title and text	221340
		Para. 9.9.3	: In the existing text, "d.c." added before "leakage"	221340
			: New sentence added	221340
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			: Existing paragraph renumbered to "9.10.2"	221340
		Para. 9.10.2	: Renumbered to "9.10.3"	221340
		Para. 9.10.3	: Renumbered to "9.10.4"	221340
		Para. 9.13.1	: Existing text deleted and new text added	221340
		Para. 9.13.2	: In the second sentence, "d.c." added before "leakage"	221340
		Para. 9.13.8	: In the text, "d.c." added before "leakage"	221340
		Para. 9.14	: In the Table, Step 5 tolerance corrected	221340
		Para. 9.15.2	: In the second sentence, "d.c." added before "leakage"	221340
		Para. 9.16.1	: Exisiting text deleted and new text added	221340
		Para. 9.16.4	: In the text, "d.c." added before "leakage"	221340
		Para. 9.17.1	: (d). "None" deleted and text added	221340
			: (e). "current" added after "leakage", and "0" deleted	221340
			: (f). In the first sentence, "d.c." added before "leakage"	221340
		Para. 9.17.2	: (d). "None" deleted and text added	221340
			: (e). "current" added after "leakage", and "0" deleted	221340
			: (f). In the first sentence, "d.c." added before "leakage"	221340
'A'	Apr. '99	P1. Cover Page		None
		P2. DCN		None
		P13. Para. 8.2.1	: New second second sentence added to last paragraph	21111
		P28. Para. 10.1.2.1	: Item (b), "PDA figure and" deleted from text	21119
			: Item (c) rewritten	21119
		P29. Para. 10.1.3.1	: Item (a), "(including PDA figure)" deleted	21119
'B'	Feb. '02	P1. Cover Page		None
		P2. DCN		None
		P27A. Para. 9.20	: New page added	221620
'C'	July '02	P1. Cover page		None
		P2. DCN		None
		P5. T of C	: Para. 9.20 added	23954
		P16. Chart II	: Surge Current Test added	23954
		P27A. Para. 9.20	: Capacitance value on drawing corrected to 20 000µF	23957

TABLE OF CONTENTS

1. INTRODUCTION

1.1 SCOPE

This specification defines the general requirements for the qualification approval, procurement, including lot acceptance testing, and delivery of Capacitors, Leadless Surface Mounted, Tantalum, Solid Electrolyte, Enclosed Anode Connection for space applications.

This specification contains the appropriate inspection and test schedules and also specifies the data documentation requirements.

1.2 APPLICABILITY

This specification is primarily applicable to the granting of qualification approval to a component in accordance with ESA/SCC Basic Specification No. 20100 and the procurement of such components from qualified Manufacturers.

2. APPLICABLE DOCUMENTS

The following documents form part of, and shall be read in conjunction with, this specification. The relevant issues shall be those in effect at the date of placing the purchase order.

2.1 ESA/SCC SPECIFICATIONS

(a) No. 20100, Requirements for the Qualification of Standard Electronic Components for Space Application.

(b) No. 20400, Internal Visual Inspection.

(c) No. 20500, External Visual Inspection.

(d) No. 20600, Preservation, Packaging and Despatch of SCC Electronic Components.

(e) No. 20900, Radiographic Inspection.

(f) No. 21300, Terms, Definitions, Abbreviations, Symbols and Units.

(g) No. 21700, General Requirements for the Marking of SCC Components.

(h) No. 22800, ESA/SCC Non-conformance Control System.

(i) No. 23500, Requirements for Lead Materials and Finishes for Components for Space Application.

(j) No. 24600, Minimum Quality System Requirements.

(k) No. 24800, Resistance to Solvents of Marking Materials and Finishes.

With the exception of ESA/SCC Basic Specification Nos. 20100, 21700, 22800 and 24600, where Manufacturers' specifications are equivalent to, or more stringent than, the ESA/SCC Basic Specifications listed above, they may be used in place of the latter, subject to the approval of the appropriate Qualifying Space Agency (QSA).

Such replacements shall be clearly identified in the applicable Process Identification Document (P.I.D.) and listed in an Appendix to the appropriate Detail Specification.

Unless otherwise stated herein, reference within the text of this specification to "the Detail Specification" shall mean the relevant ESA/SCC Detail Specification.

2.2 OTHER (REFERENCE) DOCUMENTS

(a) ESA PSS-01-702, A Thermal Vacuum Test for the Screening of Space Materials.

(b) IEC Publication No. 68, Basic Environmental Testing Procedures.

(c) IEC Publication No. 384, Fixed Capacitors for Use in Electronic Equipment.

(d) IEC Publication No. 410, Sampling Procedures and Tables for Inspection by Attributes.

2.3 ORDER OF PRECEDENCE

For the purpose of interpretation and in the case of conflict with regard to documentation, the following order of precedence shall apply:-

(a) ESA/SCC Detail Specification.

(b) ESA/SCC Generic Specification.

(c) ESA/SCC Basic Specification.

(d) Other documents if referenced herein.

3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

The terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply.

4. REQUIREMENTS

4.1 GENERAL

The test requirements for qualification approval of a component shall comprise final production tests (see Chart II), burn-in and electrical measurements to testing level 'B' (see Chart III) and qualification testing (see Chart IV).

The test requirements for procurement of components shall comprise final production tests (see Chart II), burn-in and electrical measurements to testing level 'B' or 'C' as required (see Chart III) together with, when applicable, a level of lot acceptance testing (see Chart V) to be specified by the Orderer.

If a Manufacturer elects to eliminate a final production test by substituting an in-process control or statistical process control procedure, the Manufacturer is still responsible for delivering components that meet all of the performance, quality and reliability requirements defined in this specification and the Detail Specification.

4.1.1 Specifications

For qualification approval, procurement (including lot acceptance testing) and delivery of components in conformity with this specification, the applicable specifications listed in Section 2 of this document shall apply in total unless otherwise specified herein or in the Detail Specification.

4.1.2 Conditions and Methods of Test

The conditions and methods of test shall be in accordance with this specification, the ESA/SCC Basic Specifications referenced herein and the Detail Specification.

4.1.3 Manufacturer's Responsibility for Performance of Tests and Inspections

The Manufacturer shall be responsible for the performance of tests and inspections required by the applicable specifications. These tests and inspections shall be performed at the plant of the Manufacturer of the components unless it is agreed by the Qualifying Space Agency prior to commencing qualification testing, or procurement, to use an approved external facility.

4.1.4 Inspection Rights

The Qualifying Space Agency (for qualification approval or for a procurement) reserve the right to monitor any of the tests and inspections scheduled in the applicable specifications.

4.1.5 Pre-encapsulation Inspection

The Manufacturer shall notify the Order at least two working weeks before the commencement of the encapsulation stage.

The Orderer shall indicate immediately whether or not he intends to witness the inspection.

4.2 QUALIFICATION APPROVAL REQUIREMENTS ON A MANUFACTURER

To obtain and maintain the qualification approval of a component, or family of components, a Manufacturer shall satisfy the requirements of ESA/SCC Basic Specification No. 20100.

4.3 DELIVERABLE COMPONENTS

Components delivered to this specification shall be processed and inspected in accordance with the relevant Process Identification Document (P.I.D.).

ESA/SCC qualified components delivered to this specification shall be produced from lots that are capable of passing all tests, and sequences of tests, that are defined in Charts IV and V. The Manufacturer shall not knowingly supply components that cannot meet this requirement. In the event that, subsequent to delivery and prior to operational use, a component is found to be in a condition such that it could not have passed these tests at the time of manufacture, this shall be grounds for rejection of the delivered lot.

Each delivered component shall be traceable to its production lot. Components delivered to this specification shall have completed satisfactorily all tests to the testing level and lot acceptance level specified in the purchase order (see Para. 4.3.2).

Components failing inspections and tests of the higher testing level (i.e level 'B') shall not be supplied against any order for components of the lower testing level.

4.3.1 Lot Failure

Lot failure may occur during special in-process controls (Para. 5), final production tests (Chart II), burn-in and electrical measurements (Chart III), qualification testing (Chart IV) or lot acceptance testing (Chart V).

Should such a failure occur, the non-conformance procedure shall be initiated in accordance with ESA/SCC Basic Specification No. 22800.

Should such failure occur during procurement, the Manufacturer shall notify the Orderer by telex within 2 working days, giving details of the number and mode of failure and the suspected cause.

In the case where qualification approval has been granted to the component, he shall, at the same time by the same means, inform the Qualifying Space Agency in order that the latter may consider its implications. No further testing shall be performed on the failed components except on instruction from the Orderer. The Orderer shall inform the Manufacturer and the Qualifying Space Agency within 2 working days of receipt of the telex, by the same means, what action shall be taken.

In the case where lot failure occurs during qualification testing, the Manufacturer shall immediately notify the appropriate QSA who will define a course of action to be followed. No further testing shall be performed on the failed components.

4.3.2 Testing and Lot Acceptance Levels

This specification defines 2 levels of testing severity which are designated by the letters 'B' and 'C' (see Chart I) and 3 levels of lot acceptance testing (see Chart V).

The Lot Acceptance levels are designated 1, 2 and 3 and comprise tests as follows:-

Level 3 (LA3) - Electrical Subgroup.

Level 2 (LA2) - Endurance Subgroups
plus Electrical Subgroup.

Level 1 (LA1) - Environmental and Mechanical Subgroup
plus Endurance Subgroup
plus Electrical Subgroup.

The required testing level and lot acceptance level shall both be specified in a purchase order.

4.4 MARKING

All components procured and delivered to this specification from a source qualified according to ESA/SCC Basic Specification No. 20100 shall be marked in accordance with ESA/SCC Basic Specification No. 21700. Thus, they shall bear the ESA symbol to signify their conformance to the ESA/SCC qualification approval requirements and full compliance with the requirements of this specification and the Detail Specification.

Components procured from sources which are not ESA/SCC qualified, provided that they fully comply with the procurement requirements of this specification and the Detail Specification, may bear the SCC marking **with the exception of the ESA symbol.**

5. PRODUCTION CONTROL

5.1 GENERAL

The minimum requirements for production control, which are equally applicable to procurement, are defined in the Process Identification Document (P.I.D.).

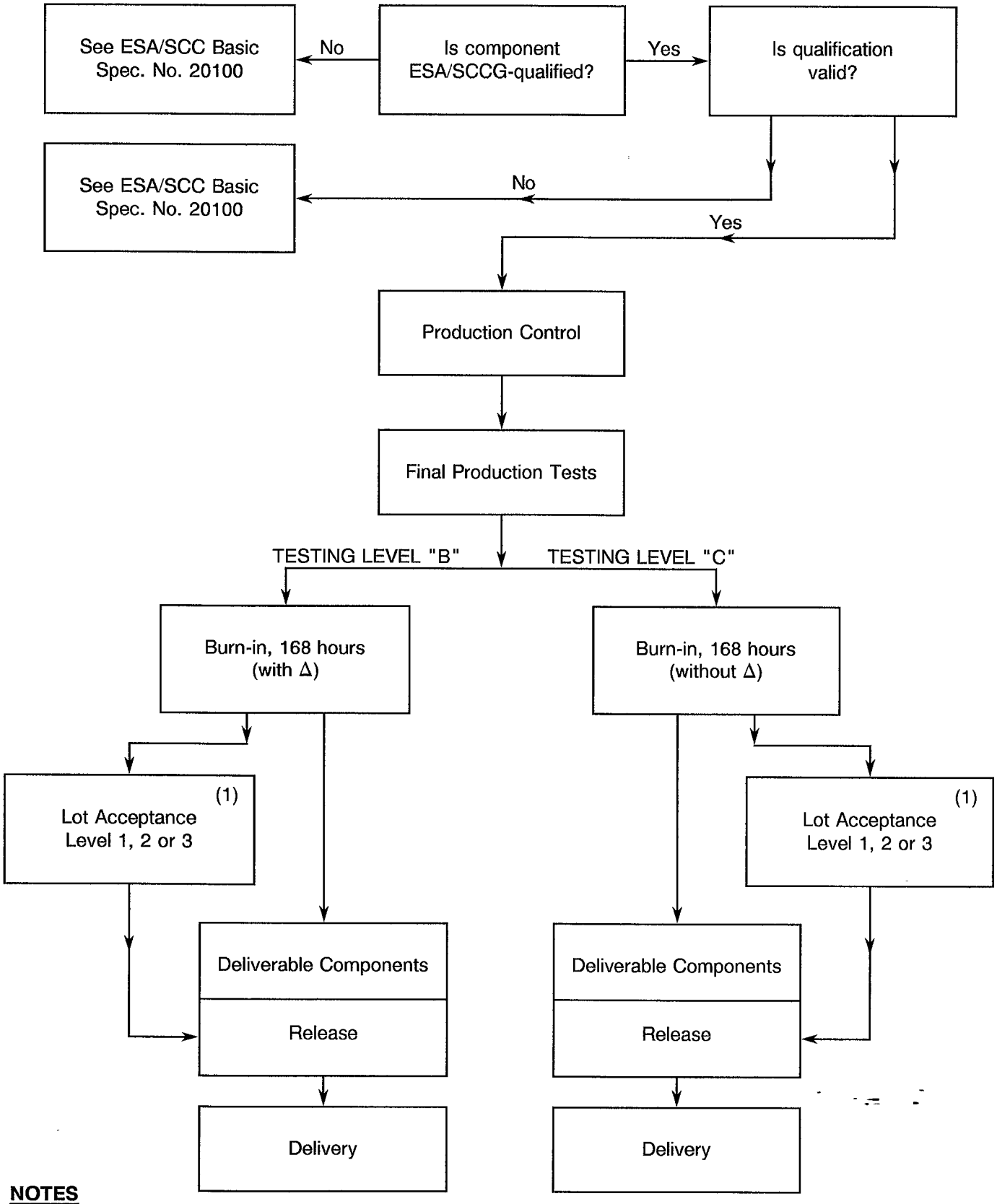
5.2 SPECIAL IN-PROCESS CONTROLS

All non-metallic materials and finishes shall, prior to the commencement of qualification testing and before any non-metallic material change to a qualified device is approved by the QSA, meet the outgassing requirements as outlined in ESA/PSS-01-702. Specific requirements for materials and finishes are specified in the Detail Specification.

5.3 Documentation

Documentation of special in-process controls shall be in accordance with the requirements of Para. 10.5 of this specification.

CHART I - TESTING LEVELS



NOTES

1. When applicable.

6. FINAL PRODUCTION TESTS

6.1 GENERAL

Unless otherwise specified in the Detail Specification, all components used for qualification testing and all components for delivery, including those submitted to lot acceptance tests, shall be subjected to tests and inspections in accordance with Chart II.

Unless otherwise specified in the Detail Specification, the tests shall be performed in the order shown.

Any components that do not meet these requirements shall be removed from the lot and at no future time be re-submitted to the requirements of this specification.

6.2 TEST METHODS AND CONDITIONS

The applicable test methods and conditions are specified in the paragraphs referenced in Chart II of this specification.

6.3 DOCUMENTATION

Documentation of final production test data shall be in accordance with the requirements of Para. 10.6 of this specification.

7. BURN-IN AND ELECTRICAL MEASUREMENTS (CHART III)

7.1 GENERAL

Unless otherwise specified in the Detail Specification, all components for qualification testing and all components for delivery, including those submitted to lot acceptance tests, shall be subjected to tests and inspections in accordance with Chart III.

Unless otherwise specified in the Detail Specification, the tests shall be performed in the order shown.

The applicable test methods and conditions are specified in the paragraphs referenced in Chart III.

Components of testing level 'B' shall be serialised prior to the tests and inspections.

7.1.1 Conditions of Test

The conditions for burn-in shall be as shown in Table 5 of the Detail Specification.

Unless otherwise specified in the Detail Specification, components of both levels 'B' and 'C' shall be subjected to a total burn-in of 168 hours. For the applicable test methods and procedures, see Para. 9.7.

7.1.2 Data Points

For components of testing level 'B', undergoing a total burn-in period of 168 hours, the data points for parameter drift value measurements shall be 0 hours (initial) and 168(+24 − 0) hours (final).

For components of testing level 'C', undergoing a total burn-in period of 168 hours, the data points for post burn-in electrical measurements shall be 168(+24 − 0) hours.

7.2 FAILURE CRITERIA

7.2.1 Parameter Drift Failure

The acceptable delta (Δ) limits are shown in Table 4 of the Detail Specification. A component of testing level 'B' shall be counted as a parameter drift failure if the changes during burn-in are larger than the delta (Δ) values specified.

7.2.2 Parameter Limit Failure

A component shall be counted as a limit failure if one or more parameters exceed the limits shown in Table 2 or 3 of the Detail Specification.

Any component which exhibits a limit failure prior to the burn-in sequence shall be rejected and not counted when determining lot rejection.

7.2.3 Other Failures

A component shall be counted as a failure in any of the following cases:-

- Mechanical failure.
- Handling failure.
- Lost component.

7.3 FAILED COMPONENTS

A component shall be considered as a failed component if it exhibits one or more of the failure modes described in Para. 7.2 of this specification.

7.4 LOT FAILURE

In the case of lot failure, the Manufacturer shall act in accordance with the requirements of Para. 4.3.1 of this specification.

7.4.1 Lot Failure during 100% Testing

If the number of components, failed on the basis of the failure criteria described in Para. 7.2, is greater than 5% (rounded upwards to the nearest whole number) of the number of components submitted to burn-in and electrical measurements, the lot shall be considered as failed.

If a lot is composed of groups of components of one family defined in one ESA/SCC Detail Specification, but separately identifiable for any reason, then the lot failure criteria shall apply separately to each identifiable group.

7.4.2 Lot Failure during Sample Testing

A lot shall be considered as failed if the number of allowable failures during sample testing in accordance with General Inspection Level II of IEC Publication No. 410 and the applicable AQL, as specified in the Detail Specification, is exceeded.

In the case where an LTPD is specified in the Detail Specification, a lot shall be considered as failed if the number of failures allowed is exceeded (see Annexe I).

If lot failure occurs in either case, 100% testing may be performed with the lot failure criteria given in Para. 7.4.1.

7.5 DOCUMENTATION

Data documentation of burn-in and electrical measurements shall be in accordance with Para. 10.7 of this specification.

8. QUALIFICATION APPROVAL AND LOT ACCEPTANCE TESTS

8.1 QUALIFICATION TESTING

8.1.1 General

Qualification testing shall be in accordance with the requirements of Chart IV of this specification. The tests to Chart IV shall be performed on the specified sample, chosen at random from components which have successfully passed the tests in Charts II and III for testing level 'B'. This sample constitutes the qualification test lot.

The qualification test lot is divided into subgroups of tests and all components assigned to a subgroup shall be subjected to all of the tests in that subgroup, in the sequence shown.

The applicable test requirements are detailed in the paragraphs referenced in Chart IV.

The conditions governing qualification testing are given in ESA/SCC Basic Specification No. 20100, Para. 5.3, and for the extension or renewal of a qualification approval in Paras. 6.3 and 6.4.

8.1.2 Distribution within the Qualification Test Lot

A minimum sample of 108 components shall be submitted to qualification testing (Chart IV). The sample shall consist of test vehicles having the lowest and highest voltages and, for these voltages, the smallest and largest case size. If there are more than 4 case sizes, an intermediate case size shall also be tested. Of each of these size/voltage combinations, the highest capacitance value and, for that value, the tightest tolerance shall be chosen.

Thus, for the qualification approval of a series, testing is required on either 2, 3, 4 or more test vehicles.

Where a series comprises more then 4 test vehicles, the minimum quantity of components per test vehicle must be:-

Subgroup I - 3 components.
Subgroup II - 3 components.
Subgroup III - 3 components.
Subgroup IV - 9 components.
Subgroup V - 6 components.
Subgroup VI - 3 components.

Where a series comprises less than 4 test vehicles, the sample shall be evenly distributed between the test vehicles.

The selected distribution shall be agreed with the Qualifying Space Agency.

8.2 LOT ACCEPTANCE TESTING

8.2.1 General

The sample sizes of the 3 lot acceptance levels are specified in Chart V. All components assigned to a subgroup shall be subjected to all of the tests of that subgroup in the sequence shown.

The tests to Chart V shall be performed on the specified sample which shall have been chosen, whenever possible, at random from the proposed delivery lot (but see Para. 8.2.3(b)).

The applicable test requirements are detailed in the paragraphs referenced in Chart V.

As a minimum for procurement of non-qualified components, lot acceptance level 3 tests shall apply. For procurement of qualified components, lot acceptance testing shall be performed if specified in a purchase order. Procurement lots ordered with a lot acceptance testing level shall be delivered only after successful completion of lot acceptance testing.

8.2.2 Distribution within the Sample for Lot Acceptance Testing

Where a Detail Specification covers a range, or series, of components that are considered similar, then it may be necessary that the sample for lot acceptance testing be comprised of component types so selected that they adequately represent all of the various mechanical, structural and electrical peculiarities of that range or series.

The distribution of the component types will normally vary from procurement to procurement and shall be specified by the Orderer, following as closely as possible the requirements specified in Para. 8.1.2 of this specification.

8.2.3 Lot Acceptance Level 3 Testing (LA3)

Lot acceptance level 3 tests are designated as the electrical subgroup and comprise electrical measurements of characteristics, and tests to prove the assembly capability of the component. For LA3 testing, the following requirements and conditions shall apply:-

(a) LA3 testing shall be performed by the Manufacturer's quality assurance personnel using dedicated quality assurance equipment whenever possible. LA3 testing shall not be a repetition of routine measurements made by production personnel during final production tests and burn-in and electrical measurements.

(b) When tests to Tables 2 and 3 of the Detail Specification have been performed on a sample basis, then the components for LA3 testing shall be selected from this sample.

(c) The electrical measurements for LA3 are considered to be non-destructive and therefore components so tested may form part of the delivery lot.

(d) The surge voltage and solderability tests are considered to be destructive and therefore components so tested shall not form part of the delivery lot.

(e) When required in the purchase order, the Manufacturer shall notify the Orderer at least 2 working weeks before the commencement of LA3 testing. The Orderer shall indicate immediately whether or not he intends to witness the tests.

8.2.4 Lot Acceptance Level 2 Testing (LA2)

Lot acceptance level 2 testing shall comprise the tests for LA3 (electrical subgroup) plus tests on an endurance subgroup. For the electrical subgroup, the requirements and conditions as for LA3 (see Para. 8.2.3) shall apply.

For the endurance subgroup, the following shall apply:-

(a) Components of testing level 'C', selected for the endurance subgroup, shall be serialised prior to the tests.

(b) The tests in this subgroup are considered destructive and therefore components (of testing level 'B' or 'C') so tested shall not form part of the delivery lot.

8.2.5 Lot Acceptance Level 1 Testing (LA1)

Lot acceptance level 1 testing shall comprise the tests for LA3 (electrical subgroup) and LA2 (endurance subgroup) plus tests on an environmental and mechanical subgroup. For the electrical and endurance subgroups, the requirements and conditions for LA3 (see Para. 8.2.3) and LA2 (see Para. 8.2.4) respectively shall apply.

For the environmental subgroup, the following shall apply:-

(a) Components of testing level 'C', selected for the environmental subgroup, shall be serialised prior to the tests.

(b) The tests in this subgroup are considered destructive and therefore components (of testing level 'B' or 'C') so tested shall not form part of the delivery lot.

8.3 FAILURE CRITERIA

The following criteria shall apply to qualification testing and to lot acceptance testing.

8.3.1 Environmental and Mechanical Test Failures

The following shall be counted as component failures:-

(a) Components which fail during tests for which the pass/fail criteria are inherent in the test method, e.g. solderability, adhesion, etc.

8.3.2 Electrical Failures

The following shall be counted as component failures:-

(a) Components which, when subjected to electrical measurements on completion of environmental tests, in accordance with either Table 2 or Table 6, as specified in the Detail Specification, fail one or more of the applicable limits.

(b) Components which, when subjected to electrical measurement at intermediate and end-points during endurance testing, in accordance with Table 6 of the Detail Specification, fail one or more of the applicable limits.

(c) Components which, when subjected to measurement of electrical characteristics, in accordance with Tables 2 and 3 of the Detail Specification, fail one or more of the applicable limits.

8.3.3 Other Failures

The following additional failures may also occur during qualification testing or lot acceptance testing:-

(a) Components failing to comply with the requirements of ESA/SCC Basic Specification No. 20500.

(b) Lost components.

8.4 FAILED COMPONENTS

A component shall be considered as failed if it exhibits one or more of the failure modes detailed in Para. 8.3 of this specification.

The allowable number of failed components per subgroup, the aggregate failure constraints and the permitted distribution of such failures are shown at the foot of Charts IV and V of this specification.

When requested by the Qualifying Space Agency or the Orderer, failure analysis of failed components shall be performed by the Manufacturer and the results provided.

Failed components from successful lots shall be marked as such and be stored at the Manufacturer's plant for 24 months.

8.5 LOT FAILURE

A lot shall be considered as failed if the allowable number of failures according to Chart IV or V of this specification, as relevant, has been exceeded.

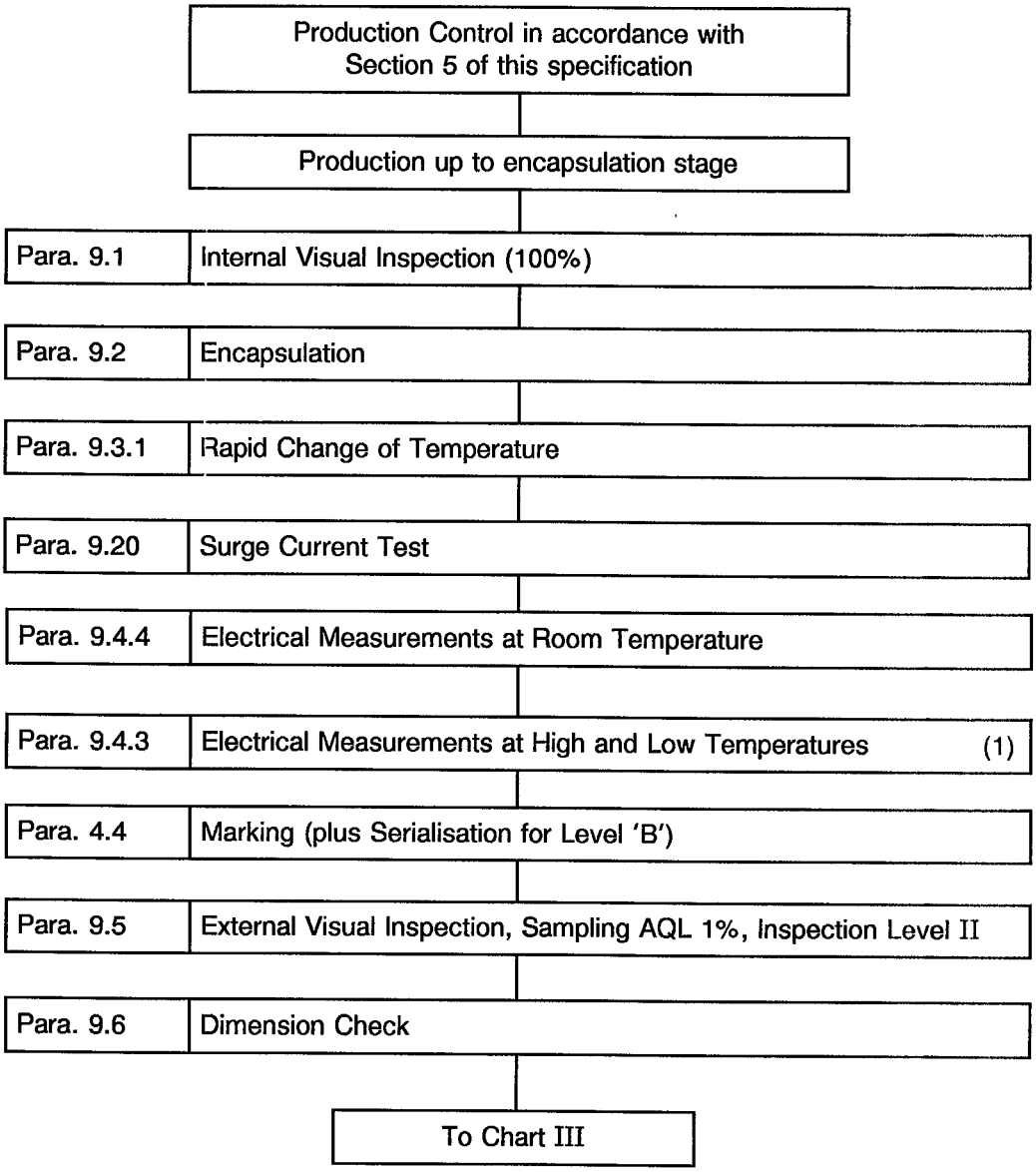
In the case of lot failure, the Manufacturer shall act in accordance with Para. 4.3.1 of this specification.

8.6 DOCUMENTATION

For qualification testing, the qualification test data shall be documented in accordance with the requirements of Para. 10.8 of this specification.

In the case of lot acceptance testing, the data shall be documented in accordance with the requirements of Para. 10.9 of this specification.

CHART II - FINAL PRODUCTION TESTS



NOTES

1. The performance of these tests is left to the Manufacturer's discretion

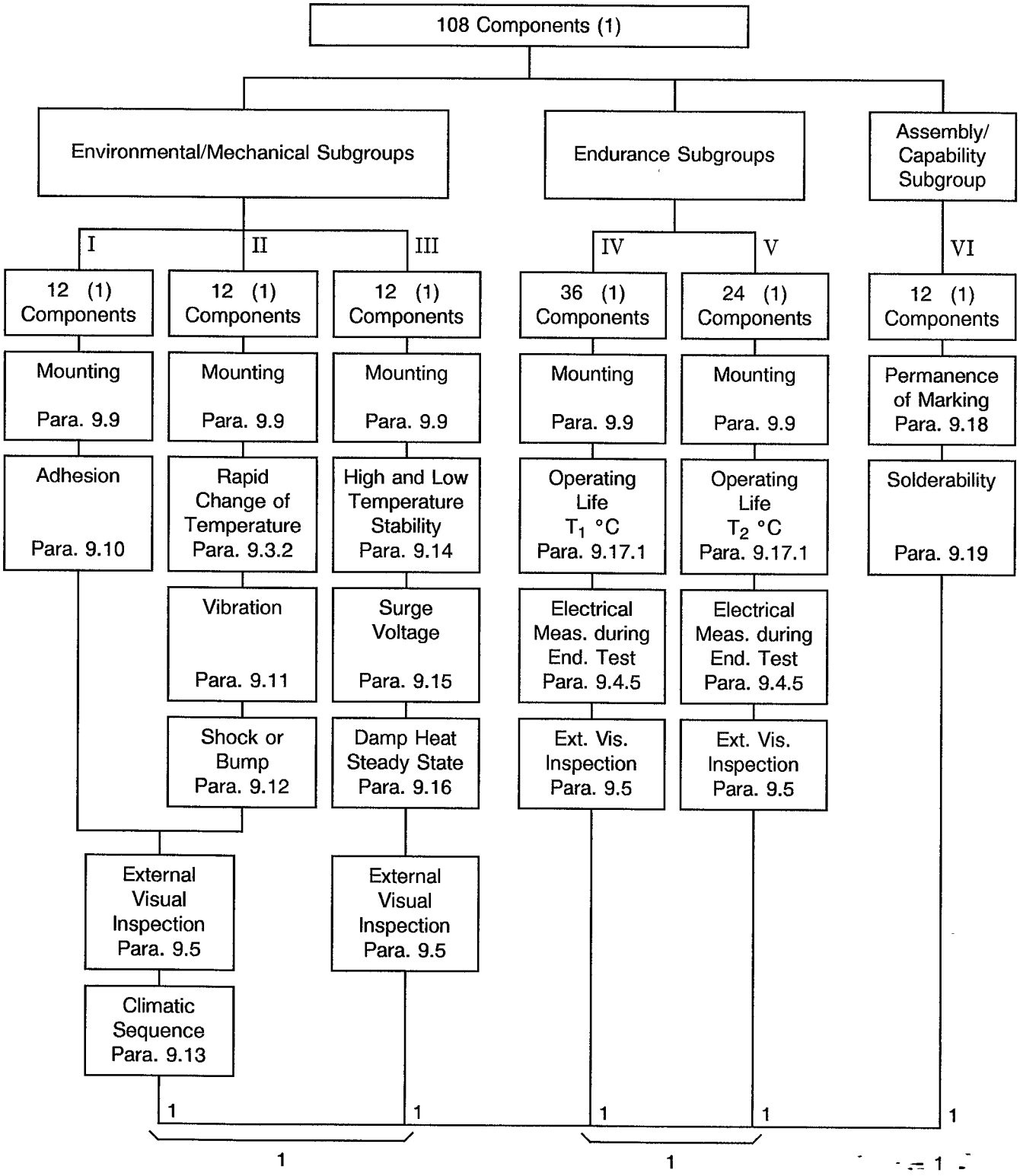
CHART III - BURN-IN AND ELECTRICAL MEASUREMENTS

		Testing Levels	
Components from Final Production Tests		B	C
Para. 9.4.2	Parameter Drift Value, Initial Measurements	X	-
Para. 7.2.1 and Para. 9.7	Burn-in, 168 hours	X	X
Para. 9.4.2	Parameter Drift Value, Final Measurements	X	-
Para. 9.4.3	Electrical Measurements at High and Low Temperatures	X	X
Para. 9.4.4	Electrical Measurements at Room Temperature (1)	X	X
Para. 9.8	Radiographic Inspection (2) (3)	X	-
Para. 9.5	External Visual Inspection	X	X
Para. 7.4	Check for Lot Failure	X	X
To Chart IV or V			

NOTES

1. The measurement of parameters for the purpose of drift value measurements need not be repeated for electrical measurements at room temperature.
2. Radiographic inspection rejects not to be counted for lot failure.
3. Radiographic inspection may be performed at any point during the test sequence shown in this chart.

CHART IV - QUALIFICATION TESTS

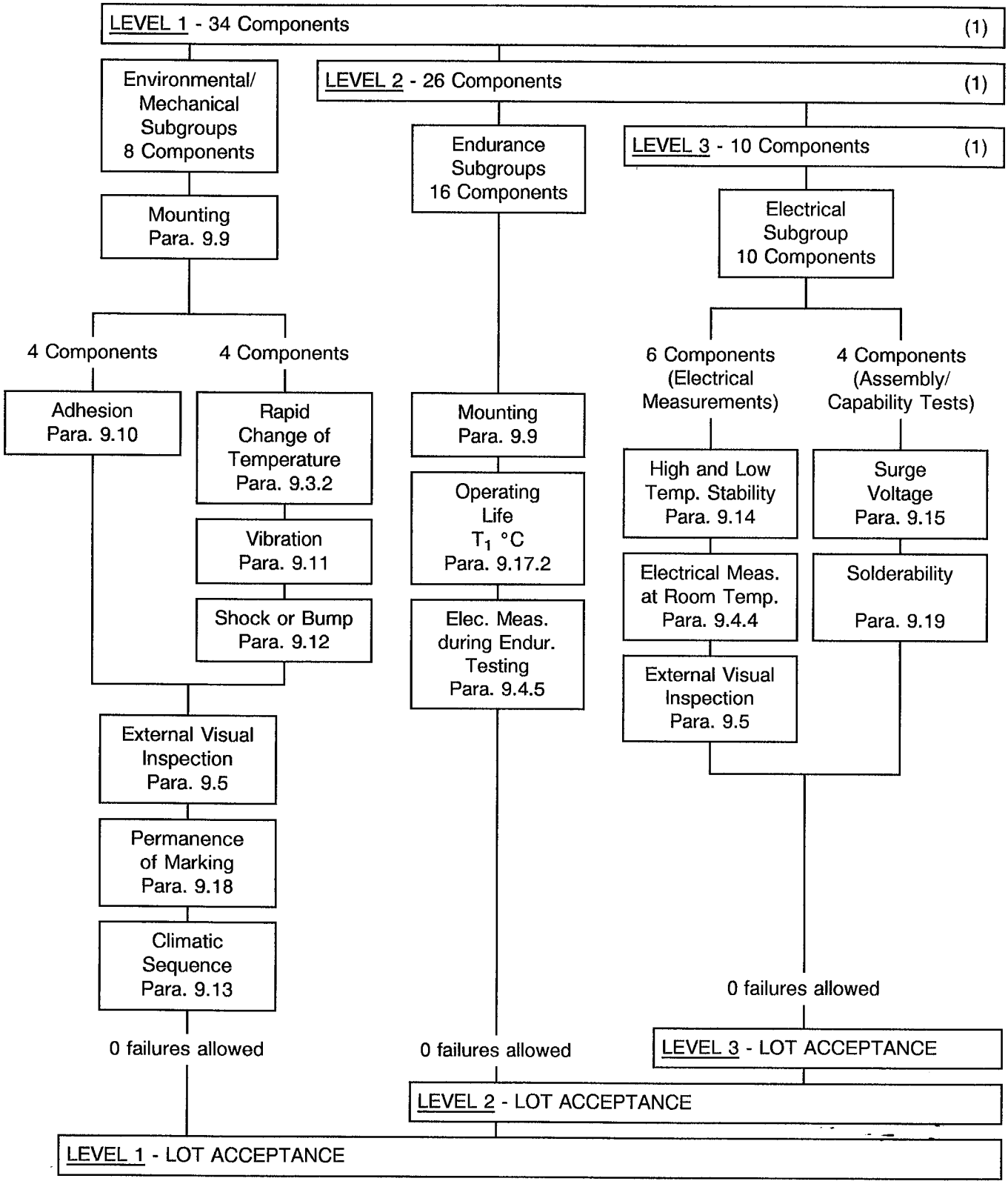


Total allowable number of failed components: 1

NOTES

1. For distribution within the subgroups, see Para. 8.1.2.

CHART V - LOT ACCEPTANCE TESTS



NOTES

1. For distribution within the sample, see Para. 8.2.2.

9. TEST METHODS AND PROCEDURES

If a Manufacturer elects to eliminate or modify a test method or procedure, the Manufacturer is still responsible for delivering components that meet all of the performance, quality and reliability requirements defined in this specification and the Detail Specification.

Documentation supporting the change shall be approved by the Qualifying Space Agency and retained by the Manufacturer. It shall be copied, when requested, to the Qualifying Space Agency.

The change shall be specified in the Detail Specification and in the P.I.D.

9.1 INTERNAL VISUAL INSPECTION

In accordance with ESA/SCC Basic Specification No. 20400.

9.2 ENCAPSULATION

In accordance with the Process Identification Document (P.I.D.).

9.3 RAPID CHANGE OF TEMPERATURE

9.3.1 Procedure for Final Production Tests (Chart II)

The capacitors shall be submitted to Test 'Na' of IEC Publication No. 68-2-14 for 5 cycles. The following details shall apply:-

T_A = minimum operating temperature as defined in Table 1(b) of the Detail Specification.
T_B = maximum operating temperature as defined in Table 1(b) of the Detail Specification.
t1 = 30 minutes, t2 = 1 minute.

Conditioning prior to the first cycle shall be 15 minutes at standard atmospheric conditions as defined in IEC Publication No. 68-1.

9.3.2 Procedure for Qualification Tests (Chart IV) and Lot Acceptance Tests (Chart V)

For capacitance change Initial Measurements, the capacitance value recorded during Para. 9.9, Mounting shall be used.

The capacitors shall be submitted to Test 'Na' of IEC Publication No. 68-2-14 for 5 cycles. The following details shall apply:-

T_A = minimum storage temperature as defined in Table 1(b) of the Detail Specification.
T_B = maximum storage temperature as defined in Table 1(b) of the Detail Specification.
t_1 = 30 minutes, t_2 = 1 minute.

Conditioning prior to the first cycle shall be 15 minutes at standard atmospheric conditions as defined in IEC Publication No. 68-1.

After a recovery period of 4 hours minimum, the capacitors shall be visually examined and there shall be no evidence of corrosion, mechanical damage or obliteration of marking.

The capacitance change, d.c. leakage current and dissipation factor shall be measured and shall be within the limits specified in Table 6 of the Detail Specification.

9.4 ELECTRICAL MEASUREMENTS

9.4.1 General

Electrical measurements and methods shall be as follows:

9.4.1.1 Capacitance

The following details shall apply:-

(a) Test Frequency

100 ± 5 or 120 ± 5 Hz.

(b) Limit of Accuracy

Measurement accuracy shall be within ± 2% of the specified limit, whether this is given as an absolute value or as a change of capacitance.

(c) Magnitude of Polarising Voltage

The maximum d.c. bias shall be 2.1 to 2.5V for all a.c. measurements.

The magnitude of the a.c. voltage shall be ≤ 0.5Vrms.

9.4.1.2 D.C. Leakage Current

The d.c. leakage current shall be measured using the d.c. rated voltage $\pm 2\%$ at the applicable test temperature after a maximum electrification period of 5 minutes. A 1000Ω resistor shall be placed in series with the capacitor to limit the charging current. A steady source of power, such as a regulated power supply, shall be used. Measurement accuracy shall be within 0.02μA.

9.4.1.3 Dissipation Factor

The dissipation factor of each capacitor shall be measured at a frequency of 100 ± 5 or 120 ± 5 Hz by means of a polarised capacitance bridge. The bridge shall provide a reading accuracy of 0.1% of the dissipation factor and a measuring accuracy of $\pm$(2% of the measured dissipation factor plus 0.001).

9.4.2 Parameter Drift Value Measurements

At each of the relevant data points for components of testing level 'B', measurements shall be made of all parameters listed in Table 4 of the Detail Specification. All values obtained shall be recorded against serial numbers and the parameter drift calculated.

9.4.3 Electrical Measurements at High and Low Temperatures

For components of testing levels 'B' and 'C', the electrical measurements at high and low temperatures shall be made in accordance with Table 3 of the Detail Specification. Where sample testing is applied, note the requirements of Para. 8.2.3(b). For testing level 'B', all values shall be recorded against serial numbers.

9.4.4 Electrical Measurements at Room Temperature

For components of testing levels 'B' and 'C', the measurements of electrical characteristics shall be made in accordance with Table 2 of the Detail Specification. Where sample testing is applied, note the requirements of Para. 8.2.3(b). For testing level 'B', all values obtained shall be recorded against serial numbers, except during Final Production Tests (Chart II).

9.4.5 Electrical measurements during Endurance Testing

At each of the relevant data points specified for endurance testing, measurements shall be made of all parameters listed in Table 6 of the Detail Specification. All values obtained shall be recorded against serial numbers.

9.5 EXTERNAL VISUAL INSPECTION

In accordance with ESA/SCC Basic Specification No. 20500.

9.6 DIMENSION CHECK

In accordance with ESA/SCC Basic Specification No. 20500 and the Detail Specification. To be performed on 5 samples per size only.

If 1 failure occurs, the complete lot shall be checked.

9.7 BURN-IN

The test shall be conducted in accordance with IEC Publication No. 384-1, Clause 4.23.

9.8 RADIOGRAPHIC INSPECTION

In accordance with ESA/SCC Basic Specification No. 20900.

9.9 MOUNTING

9.9.1 Procedure

The capacitors shall be mounted on a suitable substrate in accordance with IEC Publication No. 384-1, Clause 4.33.

9.9.2 Final Examination

The terminals shall be examined for good tinning as evidenced by the flowing of the solder with wetting of the terminals.

9.9.3 Final Measurements

The capacitance, d.c. leakage current and dissipation factor shall be measured and shall be within the limits specified in Table 6 of the Detail Specification. The capacitance value measured shall be recorded.

9.10 ADHESION

9.10.1 Initial Measurements

The capacitance value recorded during Para. 9.9, Mounting shall be used.

9.10.2 Procedure

A force of 5N shall be applied normal to the line joining the terminations and in a plane parallel to the substrate. The force shall be applied progressively (without any shock) and then be maintained for a period of 10 ± 1 seconds.

9.10.3 Final Examination

There shall be no evidence of damage or loosening of the component from the substrate.

9.10.4 Final Measurements

The capacitance change shall be measured and shall be within the limits specified in Table 6 of the Detail Specification.

9.11 VIBRATION

9.11.1 Mounting

The capacitors shall be mounted on a substrate which shall be mechanically connected to the vibration generator either directly or by means of a fixture as specified below. Mounting fixtures shall be such that they enable the specimen to be vibrated in 3 mutually perpendicular axes in turn, which should be so chosen that faults are likely to be revealed.

If external connections, necessary for measuring and supply purposes, are specified in the Detail Specification, they should add the minimum restraint and mass.

9.11.2 Procedure

The components shall be subjected to Test 'Fc' of IEC Publication No. 68-2-6.

Sweep frequency: 10-2000-10 Hz.

The entire frequency range of 10 to 2000 Hz and return to 10 Hz shall be traversed in 20 minutes. This cycle shall be performed 12 times in each of the 3 directions (a total of 36 times), so that the motion is applied for a total period of approximately 12 hours.

The vibration amplitude shall be 3.0mm from 10Hz to the higher cross-over frequency and then 20g acceleration to 2000Hz.

Unless otherwise stated in the Detail Specification, no potential shall be applied between the terminals of the capacitors under test.

9.11.3 Measurement during Vibration

During the last cycle in each direction, an electrical measurement shall be made to determine intermittent operation, intermittent contacts of 0.5ms or longer duration, arcing or open or short circuit.

9.11.4 Final Examination

After vibration, the capacitors shall be visually examined and there shall be no evidence of damage.

9.12 SHOCK OR BUMP

9.12.1 Shock

9.12.1.1 Mounting

As per Para. 9.11.1, the word 'vibration' to be replaced by 'shock'.

9.12.1.2 Procedure

The components shall be subjected to Test 'Ea' of IEC Publication No. 68-2-27. Unless otherwise specified in the Detail Specification, the following conditions shall apply:

- Shape of shock pulse: half sine.
- Peak acceleration: 50g.
- Duration of pulse: 11ms.
- Number of shocks: 18 (3 shocks in each direction along the 3 perpendicular axes of the test specimen).

9.12.1.3 Final Examination

As per Para. 9.11.4, the word 'vibration' to be replaced by 'shock'.

9.12.2 Bump

9.12.2.1 Mounting

As per Para. 9.11.1, the word 'vibration' to be replaced by 'bump'.

9.12.1.2 Procedure

The components shall be subjected to Test 'Eb' of IEC Publication No. 68-2-29. Unless otherwise specified in the Detail Specification, the following conditions shall apply:

- Peak acceleration: $390 m/s^2$.
- Duration of pulse: 6.0ms.
- Number of bumps: 4000 ± 10.

9.12.1.3 Final Examination

As per Para. 9.11.4, the word 'vibration' to be replaced by 'bump'.

9.13 CLIMATIC SEQUENCE

9.13.1 Initial Measurements

The capacitance value recorded during Para. 9.9, Mounting shall be used.

9.13.2 Dry Heat

The components shall be subjected to Test 'Ba' of IEC Publication No. 68-2-2. Duration: 2 hours. Maximum storage temperature as prescribed in the Detail Specification (Table 1(b)).

While still at the specified high temperature and at the end of the period of high temperature, the d.c. leakage current shall be measured and the value shall be within the limits specified in Table 6 of the Detail Specification.

9.13.3 Damp Heat, Accelerated, First Cycle

Unless otherwise specified in the Detail Specification, the components shall be subjected to Test 'Db', severity b, variant 2 of IEC Publication No. 68-2-30, 1 cycle. After recovery, the capacitors shall be subjected immediately to the cold test.

9.13.4 Cold Test

The components shall be subjected to Test 'Aa' of IEC Publication No. 68-2-1.

Duration: 2 hours. Minimum storage temperature as specified in the Detail Specification (Table 1(b)).

9.13.5 Low Air Pressure

The components shall be subjected to Test 'M' of IEC Publication No. 68-2-13 under the following conditions:

- 1 to 2 minutes at 85mbar.
- Temperature: +15 to +35°C.
- The voltage U_r shall be applied for 1 to 2 minutes immediately after the pressure of 85mbar has been attained.

9.13.6 Damp Heat, Accelerated, Remaining Cycles

The components shall be subjected to Test 'Db', severity b, variant 2 of IEC Publication No. 68-2-30, 5 cycles.

9.13.7 Recovery and Final Inspection

After a recovery period of 1 to 24 hours, the capacitors shall be visually inspected according to ESA/SCC Basic Specification No. 20500.

9.13.8 Final Measurements

The capacitance change, d.c. leakage current and dissipation factor shall be measured and shall be within the limits specified in Table 6 of the Detail Specification.

9.14 HIGH AND LOW TEMPERATURE STABILITY

The measurements shall be made as specified in Table 6 of the Detail Specification at the temperatures specified hereafter, except that d.c. leakage measurements at the minimum operating temperature (Step 2) are not required.

The components shall be brought to thermal stability at each temperature. Thermal stability will have been reached when no further change in capacitance is observed between 2 successive measurements taken at 15 minute intervals.

STEP	TEST TEMPERATURE (°C)
1	+22 ± 3
2	Minimum Operating Temperature (+3 − 0) (Detail Specification Table 1(b))
3	+22 ± 3
4	Rated Temperature ±3 (Detail Specification Table 1(b))
5	Category Temperature (+0 − 3) (Detail Specification Table 1(b))
6	+22 ± 3

9.15 SURGE VOLTAGE

9.15.1 Procedure

The capacitors shall be subjected to 1000 cycles of the applicable surge voltage as specified in the Detail Specification (Table 1(b)). The temperature during cycling shall be the rated temperature as specified in the Detail Specification (Figure 1). Each cycle shall consist of a 30 second surge voltage application, followed by a 30 second discharge period.

Voltage application shall be through a resistor of 33Ω ± 5%. Each surge voltage cycle shall be performed in such a manner that the component is shorted terminal to terminal through a copper bar or equivalent low resistance at the end of the 30 second application. An alternative method of shorting the capacitors is to discharge through the same resistance used for charging.

9.15.2 Final Measurements

The components shall be stabilised at room temperature. The capacitance, d.c. leakage current and dissipation factor shall be measured and shall be within the limits specified in Table 6 of the Detail Specification.

9.16 DAMP HEAT STEADY STATE

9.16.1 Initial Measurements

The capacitance value recorded during Para. 9.9, Mounting shall be used.

9.16.2 Procedure

The components shall be subjected to Test 'Ca' of IEC Publication No. 68-2-3 for 56 days with no voltage applied unless otherwise specified in the Detail Specification.

9.16.3 Recovery and Final Examination

After a recovery period of 1 to 2 hours the capacitors shall be visually examined and there shall be no evidence of damage.

9.16.4 Final Measurements

The capacitance change, d.c. leakage current and dissipation factor shall be measured and shall be within the limits specified in Table 6 of the Detail Specification.

9.17 OPERATING LIFE

9.17.1 Operating Life during Qualification Testing

(a) Duration

2000 hours.

(b) Test Temperatures

The test temperatures shall be the rated temperature (Detail Specification, Table 1(b)) in subgroup IV (T_1) and the category temperature (Detail Specification, Table 1(b)) in subgroup V (T_2).

(c) Operating Conditions

Rated d.c. voltage for the test at the rated temperature (T_1), or category voltage for the test at the category temperature (T_2) shall be applied gradually (but time not to exceed 5 minutes), either by a slow build-up of the voltage or through a resistor which shall be shorted out within 5 minutes. The voltage shall be applied continuously except for measurement periods. The impedance of the voltage source, as seen from the terminals of each component shall not exceed 3.0Ω.

Storage batteries or an electronic power supply, capable of supplying at least 1.0A when a capacitor is shorted, shall be used.

(d) Initial Measurements

The capacitance value recorded during Para. 9.9, Mounting shall be used.

(e) Intermediate Data Points

During exposure, d.c. leakage current (as specified in Para. 9.4.1.2) shall be measured at 250 ± 48 hours and 1000 ± 48 hours at the applicable high test temperature as specified in Table 6 of the Detail Specification and the values shall be within the specified limits.

(f) End Data Points

After the capacitors have been returned to room temperature the capacitance change, d.c. leakage current and dissipation factor shall be measured and shall be within the limits specified in Table 6 of the Detail Specification.

In the case where Table 6 specifies "changes", the drift shall always be related to the 0 hour measurement.

(g) Visual Examination

On completion of the operating life tests, the capacitors shall be visually examined. There shall be no evidence of damage.

9.17.2 Operating Life during Lot Acceptance Testing

(a) Duration

1000 hours.

(b) Test Temperatures

The test temperature shall be the rated temperature (Detail Specification, Table 1(b)) (T_1).

(c) Operating Conditions

Rated d.c. voltage shall be applied gradually (but time not to exceed 5 minutes), either by a slow build-up of the voltage or through a resistor which shall be shorted out within 5 minutes. The voltage shall be applied continuously except for measurement periods. The impedance of the voltage source, as seen from the terminals of each component shall not exceed 3.0Ω.

Storage batteries or an electronic power supply, capable of supplying at least 1.0A when a capacitor is shorted, shall be used.

(d) Initial Measurements

The capacitance value recorded during Para. 9.9, Mounting shall be used.

(e) Intermediate Data Points

During exposure, d.c. leakage current (as specified in Para. 9.4.1.2) shall be measured at 250 ± 48 hours at the applicable high test temperature as specified in Table 6 of the Detail Specification and the values shall be within the specified limits.

(f) End Data Points

After the capacitors have been returned to room temperature the capacitance change, d.c. leakage current and dissipation factor shall be measured and shall be within the limits specified in Table 6 of the Detail Specification.

In the case where Table 6 specifies "changes", the drift shall always be related to the 0 hour measurement.

(g) Visual Examination

On completion of the operating life tests, the capacitors shall be visually examined. There shall be no evidence of damage.

9.18 PERMANENCE OF MARKING

In accordance with ESA/SCC Basic Specification No. 24800.

9.19 SOLDERABILITY

9.19.1 Preconditioning

Prior to the test the capacitors shall be preconditioned (dry aged) for 4 hours at +155°C.

9.19.2 Procedure

The components shall be subjected to Test 'Ta', Method 1 of IEC Publication No. 68-2-20, using the solder bath method.

The capacitors shall be completely immersed. The temperature shall be +235 ± 5°C and the duration of immersion 4 ± 1 seconds unless otherwise specified in the Detail Specification.

9.19.3 Final Examination

At least 75% of the terminations shall be covered by a smooth solder coating. The remaining 25% may contain small pin holes or rough spots, but these shall not be concentrated in one area.

When the test procedures have been carried out, the components shall be visually examined. There shall be no evidence of damage.

9.20 Surge Current Test

A surge current test shall be performed at room temperature as follows:

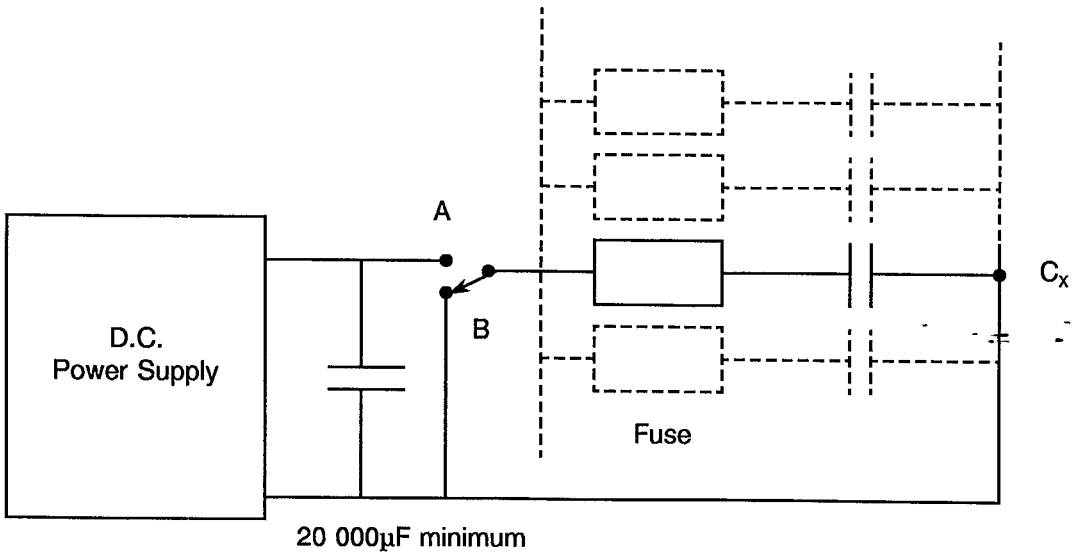
(a) After rapid change of temperature of Chart II.

(b) Without intermediate electrical measurements between rapid change of temperature and surge current test.

(c) Each capacitor under test shall be submitted to 5 charge/discharge surge current cycles of at least 0.5s per charge and 0.5s per discharge, at the rated voltage of the capacitor under test.

(d) The test circuit shall comply with the following conditions (see Figure below):

- The test shall be performed on an individual capacitor.
- The power supply used for charging the energy storage capacitor bank shall be capable of supplying a regulated d.c. voltage, variable from 0 to 100V minimum at a 10A minimum current capability.
- The capacitor shall be placed across the d.c. power supply and shall be continually charged. It shall consist of very low ESR aluminium electrolytic capacitors , connected in parallel, having a capacitance of 20 000µF minimum.
- The bank capacitor shall provide, across the capacitor under test, a peak surge current value equal to the test voltage divided per ESR of the capacitor under test plus total circuit resistance. The requirement shall be verified for each test line.
- For calibration, the monitoring of the voltage across a capacitor of 47µF ±10% 35V under test shall demonstrate that the peak voltage across the capacitor during charging is rated voltage ±5.0% and that 90% of rated voltage is achieved within the first 100µs. This requirement shall be verified for each test line.
- A 30A mercury relay or equivalent shall be used to switch the capacitor under test to the energy bank for charge and into a short-circuit of not more than 0.2Ω maximum for discharge.
- The total resistance of all wiring between the energy source and the capacitor under test, including the mercury relay, the ESR of the capacitor bank and the fuse, shall not exceed 0.5Ω maximum.
- The fuse in the test circuit shall have a rating of not less than 1A and not more than 5A. A fuse shall be placed in series with each capacitor undergoing the test.
- A capacitor under test shall be considered a failure either when the fuse blows or the d.c. leakage current limit exceeds the nominal value.



10. DATA DOCUMENTATION

10.1 GENERAL

For the qualification approval records and with each component delivery, a data documentation package is required. Depending on the testing level and lot acceptance level specified for the component, this package shall be compiled from:-

(a) Cover sheet (or sheets).

(b) List of equipment (testing and measuring).

(c) List of test references.

(d) Special in-process control test data.

(e) Final production test data (Chart II) (but see Para. 10.6).

(f) Burn-in and electrical measurement data (Chart III).

(g) Qualification test data (Chart IV).

(h) Lot acceptance test data (Chart V) (when applicable).

(i) Failed component list (see Paras. 7.3 and 8.4), and failure analysis report (see Para. 8.4).

(j) Certificate of Conformity.

(k) Radiographic inspection photographs.

Items (a) to (k) inclusive shall be grouped, preferably as subpackages, and for identification purposes, each page shall include the following information:-

- ESA/SCC Component Number.
- Manufacturer's name.
- Lot identification.
- Date of establishment of the document.
- Page number.

10.1.1 Qualification Approval

In the case of qualification approval, the items listed in Para. 10.1(a) to (k) less item (h) are required.

10.1.2 Testing Level 'B'

10.1.2.1 Qualified Components

For deliveries of qualified components, the following documentation shall be supplied:-

(a) Cover sheet (if all of the information is not included on the Certificate of Conformity).

(b) Certificate of Conformity (including range of delivered serial numbers).

(c) Attributes record of measurements, tests and inspections performed in Chart II, Chart III (including PDA figure) and Chart V (where applicable).

(d) Failed components list.

10.1.2.2 Unqualified Components

For deliveries of unqualified components, the documentation to be supplied shall be in accordance with Para. 10.1.2.1 plus the following:-

(a) Read and record data from Chart III.

(b) Special in-process control data (where applicable).

(c) Failure analysis report on failed components.

10.1.3 Testing Level "C"

10.1.3.1 Qualified Components

For deliveries of qualified components, the following documentation shall be supplied:-

(a) Certificate of Conformity.

10.1.3.2 Unqualified Components

For deliveries of unqualified components, the documentation to be supplied shall be in accordance with Para. 10.1.3.1 plus the following:-

(a) Cover sheet (if all of the information is not included on the Certificate of Conformity).

(b) Attributes record of all measurements, tests and inspections performed in Charts II, III and V (when applicable).

(c) Failed components list (including Failure Analysis Report).

(d) Special in-process control data (when applicable).

10.1.4 Data Retention/Data Access

If not delivered, all data shall be retained by the Manufacturer for a minimum of 5 years during which time it shall be available to the Qualifying Space Agency and the Orderer, if requested, for review. The Manufacturer shall deliver variables Data/Reports to the Orderer if required by the Purchase Order.

10.2 COVER SHEET(S)

The cover sheet (or sheets) of the data documentation package shall include as a minimum:-

(a) Reference to the Detail Specification, including issue and date.

(b) Reference to the applicable ESA/SCC Generic Specification, including issue and date.

(c) Component type and number.

(d) Lot identification.

(e) Range of delivered serial numbers (for components of testing level 'B').

(f) Number of purchase order.

(g) Information relative to any additions to this specification and/or the Detail Specification.

(h) Manufacturer's name and address.

(i) Location of the manufacturing plant.

(j) Signature on behalf of the Manufacturer.

(k) Total number of pages of the data package.

10.3 LIST OF EQUIPMENT USED

A list of equipment used for tests and measurements shall be prepared, if not in accordance with the data given in the Process Identification Document (P.I.D.). Where applicable, this list shall contain inventory number, Manufacturer's type number, serial number, etc. This list shall indicate for which tests such equipment was used.

10.4 LIST OF TEST REFERENCES

This list shall include all Manufacturer's references or codes which are necessary to correlate the test data provided with the applicable tests specified in the tables of the Detail Specification.

10.5 SPECIAL IN-PROCESS CONTROL DATA

Where applicable, the data shall be as specified in the Detail Specification.

10.6 FINAL PRODUCTION TEST DATA (CHART II)

A test result summary shall be compiled showing the total number of components submitted to, and the total number rejected, after each of the following tests:

- Internal visual inspection (Para. 9.1).
- Rapid change of temperature (Para. 9.3.1).
- Electrical measurements at room temperature (Para. 9.4.4).
- External visual inspection (Para. 9.5).
- Dimension check (Para. 9.6).

The final production test data shall form an integral part of the data documentation package, but it is not a mandatory requirement that it be delivered with the qualification lot or delivery lot. However, the data package to be delivered shall contain the information as detailed in Paras. 10.1.2 and 10.1.3 or at least shall contain a list of final production tests actually performed and a certification that the data is available for review.

10.7 BURN-IN AND ELECTRICAL MEASUREMENT DATA (CHART III)

10.7.1 Testing Level 'B'

For components of testing level 'B' all data shall refer to the relevant serial numbers. Against these serial number, data shall be recorded for the following:-

(a) 0-hour measurement for burn-in.

(b) 168-hour measurement for burn-in.

(c) Delta (Δ) values after burn-in.

(d) Values obtained during measurements at high and low temperatures (Table 3 of the Detail Specification).

(e) Values obtained during measurements at room temperature (Table 2 of the Detail Specification).

(f) Failures during external visual inspection.

(g) Photographs from radiographic inspection, including those of reject components.

10.7.2 Testing Level 'C'

For components of testing level 'C', a test result summary (i.e. the total number of components subjected to, and the total number rejected from, each of the tests and inspections) shall be prepared.

10.8 QUALIFICATION TEST DATA (CHART IV)

All data shall be referenced to the relevant serial numbers. Detailed records shall be provided of the components submitted to each test in each of the subgroups and of those rejected.

Detailed data shall be provided of all electrical measurements made in accordance with Tables 2 and 6 of the Detail Specification, as and where applicable.

10.9 LOT ACCEPTANCE TEST DATA (CHART V)

10.9.1 Testing Level 'B'

All data shall be referenced to the relevant serial numbers. Detailed records shall be provided of the components submitted to each test in each of the subgroups (as relevant to the lot acceptance level) and of those rejected.

Detailed data shall be provided of all electrical measurements made in accordance with Tables 2, 3 and 6 of the Detail Specification, as and where applicable.

10.9.2 Testing Level 'C'

A test result summary (i.e. the total number of components submitted to, and the total number rejected from, each of the tests and inspections) as relevant to the lot acceptance level, shall be provided.

In the case of lot acceptance 2 testing, all data in respect of electrical measurements made in accordance with Table 6 of the Detail Specification shall be referenced to the relevant serial numbers (see Para. 8.2.4(a)).

In the case of lot acceptance 1 testing, all data in respect of electrical measurements made in accordance with Tables 2, 3 and 6 of the Detail Specification shall be referenced to the relevant serial numbers (see Para. 8.2.5(a)).

10.10 FAILED COMPONENTS LIST AND FAILURE ANALYSIS REPORT

The failed component list and failure analysis report shall provide full details of:-

(a) The reference number and description of the test or measurement performed as defined in this specification and/or the Detail Specification.

(b) The serial number (if applicable) of the failed component.

(c) The failed parameter and the failure mode of the component.

(d) A detailed failure analysis, if requested.

10.11 CERTIFICATE OF CONFORMITY

A Certificate of Conformity shall be established as defined in ESA/SCC Basic Specification No. 20100.

11. DELIVERY

For qualification approval, the disposition of the qualification test lot and its related documentation shall be as specified in ESA/SCC Basic Specification No. 20100 and the relevant paragraphs of Section 10 of this specification.

For procurement, for each order, the items forming the delivery are:-

(a) The delivery lot.

(b) The components used for lot acceptance testing, (when applicable), but not forming part of the delivery lot (see Para's. 8.2.3(d), 8.2.4(b) and 8.2.5(b)).

(c) The relevant documentation in accordance with the requirements of Section 10 of this specification.

In the case of a component for which a valid qualification approval is in force, all data of all components submitted to LA1 and LA2 testing shall also be copied, when requested, to the relevant Qualifying Space Agency.

12. PACKAGING AND DESPATCH

The packaging and despatch of components to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 20600.

ANNEXE I

LTPD SAMPLING PLAN FOR LOT SIZES GREATER THAN 200

Minimum size of sample to be tested to assure, with a 90% confidence, that a lot whose Percent Defective equals the specified LTPD is not accepted (single sample).

Max. Percent Defective (LTPD) or λ	50	30	20	15	10	7	5	3	2	1.5	1	0.7	0.5	0.3	0.2	0.15	0.1
Acceptance Number (c) (r=c+1)	MINIMUM SAMPLE SIZES (FOR DEVICE-HOURS REQUIRED FOR LIFE TEST, MULTIPLY BY 1000)																
0	5 (1.03)	8 (0.64)	11 (0.46)	15 (0.34)	22 (0.23)	32 (0.16)	45 (0.11)	76 (0.07)	116 (0.04)	153 (0.03)	231 (0.02)	328 (0.02)	461 (0.01)	767 (0.007)	1152 (0.005)	1534 (0.003)	2303 (0.002)
1	8 (4.4)	13 (2.7)	18 (2.0)	25 (1.4)	38 (0.94)	55 (0.65)	77 (0.46)	129 (0.28)	195 (0.18)	258 (0.14)	390 (0.09)	555 (0.06)	778 (0.045)	1296 (0.027)	1946 (0.018)	2592 (0.013)	3891 (0.009)
2	11 (7.4)	18 (4.5)	25 (3.4)	34 (2.24)	52 (1.6)	75 (1.1)	105 (0.78)	176 (0.47)	266 (0.31)	354 (0.23)	533 (0.15)	759 (0.11)	1065 (0.080)	1773 (0.045)	2662 (0.031)	3547 (0.022)	5323 (0.015)
3	13 (10.5)	22 (6.2)	32 (4.4)	43 (3.2)	65 (2.1)	94 (1.5)	132 (1.0)	221 (0.62)	333 (0.41)	444 (0.31)	668 (0.20)	953 (0.14)	1337 (0.10)	2226 (0.062)	3341 (0.041)	4452 (0.031)	6681 (0.018)
4	16 (12.3)	27 (7.3)	38 (5.3)	52 (3.9)	78 (2.6)	113 (1.8)	158 (1.3)	265 (0.75)	398 (0.50)	531 (0.37)	798 (0.25)	1140 (0.17)	1599 (0.12)	2663 (0.074)	3997 (0.049)	5327 (0.037)	7994 (0.025)
5	19 (13.8)	31 (8.4)	45 (6.0)	60 (4.4)	91 (2.9)	131 (2.0)	184 (1.4)	308 (0.85)	462 (0.57)	617 (0.42)	927 (0.28)	1323 (0.20)	1855 (0.14)	3090 (0.085)	4638 (0.056)	6181 (0.042)	9275 (0.028)
6	21 (15.6)	35 (9.4)	51 (6.6)	68 (4.9)	104 (3.2)	149 (2.2)	209 (1.6)	349 (0.94)	528 (0.62)	700 (0.47)	1054 (0.31)	1503 (0.22)	2107 (0.155)	3509 (0.093)	5267 (0.062)	7019 (0.047)	10533 (0.031)
7	24 (16.6)	39 (10.2)	57 (7.2)	77 (5.3)	116 (3.5)	166 (2.4)	234 (1.7)	390 (1.0)	589 (0.67)	783 (0.51)	1178 (0.34)	1680 (0.24)	2355 (0.17)	3922 (0.101)	5886 (0.067)	7845 (0.051)	11771 (0.034)
8	26 (18.1)	43 (10.9)	63 (7.7)	85 (5.6)	128 (3.7)	184 (2.6)	258 (1.8)	431 (1.1)	648 (0.72)	864 (0.54)	1300 (0.36)	1854 (0.25)	2599 (0.18)	4329 (0.108)	6498 (0.072)	8660 (0.054)	12995 (0.036)
9	28 (19.4)	47 (11.5)	69 (8.1)	93 (6.0)	140 (3.9)	201 (2.7)	282 (1.9)	471 (1.2)	709 (0.77)	945 (0.58)	1421 (0.38)	2027 (0.27)	2842 (0.19)	4733 (0.114)	7103 (0.077)	9468 (0.057)	14206 (0.038)
10	31 (19.9)	51 (12.1)	75 (8.4)	100 (6.3)	152 (4.1)	218 (2.9)	306 (2.0)	511 (1.2)	770 (0.80)	1025 (0.60)	1541 (0.40)	2199 (0.28)	3082 (0.20)	5133 (0.120)	7704 (0.080)	10268 (0.060)	15407 (0.040)
11	33 (21.0)	54 (12.8)	83 (8.3)	111 (6.2)	166 (4.2)	238 (2.9)	332 (2.1)	555 (1.2)	832 (0.83)	1109 (0.62)	1664 (0.42)	2378 (0.29)	3323 (0.21)	5546 (0.12)	8319 (0.083)	11092 (0.062)	16638 (0.042)
12	36 (21.4)	59 (13.0)	89 (8.6)	119 (6.5)	178 (4.3)	254 (3.0)	356 (2.2)	594 (1.3)	890 (0.86)	1187 (0.65)	1781 (0.43)	2544 (0.3)	3562 (0.22)	5936 (0.13)	8904 (0.086)	11872 (0.065)	17808 (0.043)
13	38 (22.3)	63 (13.4)	95 (8.9)	126 (6.7)	190 (4.5)	271 (3.1)	379 (2.26)	632 (1.3)	948 (0.89)	1264 (0.67)	1896 (0.44)	2709 (0.31)	3793 (0.22)	6321 (0.134)	9482 (0.089)	12643 (0.067)	18964 (0.045)
14	40 (23.1)	67 (13.8)	101 (9.2)	134 (6.9)	201 (4.6)	288 (3.2)	403 (2.3)	672 (1.4)	1007 (0.92)	1343 (0.69)	2015 (0.46)	2878 (0.32)	4029 (0.23)	6716 (0.138)	10073 (0.092)	13431 (0.069)	20146 (0.046)
15	43 (23.3)	71 (14.1)	107 (9.4)	142 (7.1)	213 (4.7)	305 (3.3)	426 (2.36)	711 (1.41)	1066 (0.94)	1422 (0.71)	2133 (0.47)	3046 (0.33)	4265 (0.235)	7108 (0.141)	10662 (0.094)	14216 (0.070)	21324 (0.047)
16	45 (24.1)	74 (14.0)	112 (9.7)	150 (7.2)	225 (4.8)	321 (3.37)	450 (2.41)	750 (1.44)	1124 (0.96)	1499 (0.72)	2249 (0.48)	3212 (0.337)	4497 (0.241)	7496 (0.144)	11244 (0.096)	14992 (0.072)	22487 (0.048)
17	47 (24.7)	79 (14.7)	118 (9.86)	158 (7.36)	236 (4.93)	338 (3.44)	473 (2.46)	788 (1.48)	1182 (0.98)	1576 (0.74)	2364 (0.49)	3377 (0.344)	4728 (0.246)	7880 (0.148)	11819 (0.098)	15759 (0.074)	23639 (0.049)
18	50 (24.9)	83 (15.0)	124 (10.0)	165 (7.54)	248 (5.02)	354 (3.51)	496 (2.51)	826 (1.51)	1239 (1.0)	1652 (0.75)	2478 (0.50)	3540 (0.351)	4956 (0.251)	8260 (0.151)	12390 (0.100)	16520 (0.075)	24780 (0.050)
19	52 (25.5)	86 (15.4)	130 (10.2)	173 (7.76)	259 (5.12)	370 (3.58)	518 (2.56)	864 (1.53)	1296 (1.02)	1728 (0.77)	2591 (0.52)	3702 (0.358)	5183 (0.256)	8638 (0.153)	12957 (0.102)	17276 (0.077)	25914 (0.051)
20	54 (26.1)	90 (15.6)	135 (10.4)	180 (7.82)	271 (5.19)	386 (3.65)	541 (2.60)	902 (1.56)	1353 (1.04)	1803 (0.78)	2705 (0.52)	3864 (0.364)	5410 (0.260)	9017- (0.156)	13526 (0.104)	18034 (0.078)	27051 (0.052)
26	65 (27.0)	109 (16.1)	163 (10.8)	217 (8.08)	326 (5.38)	466 (3.76)	652 (2.69)	1086 (1.61)	1629 (1.08)	2173 (0.807)	3259 (0.538)	4656 (0.376)	6518 (0.269)	10863 (0.161)	16295 (0.108)	21726 (0.081)	32589 (0.054)

NOTES

(1) Sample sizes are based upon the Poisson exponential binomial limit.

(2) The minimum quality (approximate AQL) required to accept (on the average) 19 of 20 lots is shown in parentheses for information only.

ANNEXE I

LTPD SAMPLING PLAN FOR LOT SIZES LESS THAN OR EQUAL TO 200

C=0

N	10	20	30	40	50	60	80	100	120	150	160	200
n	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD
2	2 2 65	2 5 66	2 5 67	2 5 67	2 5 67	2 5 68	2 5 68	2.5 68	2 5 68	2 5 68	2 5 68	2 5 68
4	1 2 36	1 2 40	1.2 42	1 2 42	1.3 42	1 3 43	1.3 43	1 3 43	1.3 43	1 3 43	1 3 44	1 3 44
5	1 0 29	1 0 33	1 0 34	1 0 35	1 0 35	1 0 35	1 0 36	1 0 36	1 0 37	1 0 37	1 0 37	1 0 37
8	0.5 15	0 6 20	0 6 22	0 6 23	0 6 23	0 6 23	0 6 24	0 7 24	0 7 24	0 7 24	0 7 24	0 7 25
10		0.4 15	0 5 17	0 5 19	0 5 19	0 5 19	0 5 20	0 5 20	0 5 20	0 5 20	0 5 20	0 5 20
16		0 2 6.9	0 25 10	0 25 11	0 3 11	0 3 12	0 3 12	0 3 13	0 3 13	0 3 13	0 3 13	0 3 13
20			0 2 6 8	0 2 8 0	0.25 8 7	0 25 9 0	0 25 9 4	0 25 10	0 25 10	0.25 10	0 25 10	0 25 11
25			0 15 4 3	0 15 5 7	0 2 6 4	0 2 6 9	0.2 7 4	0 2 7 5	0 2 7 6	0 2 7 7	0 2 7 8	0 2 7 9
32				0 1 3 7	0 1 4 4	0.1 5 0	0 1 5 5	0 1 5.9	0 15 6 0	0 15 6 2	0.15 6 3	0 15 6 3
40					0 1 3 0	0 1 3 4	0 1 4.0	0 1 4 5	0 1 4 6	0 1 4 9	0 1 5 0	0 15 5 0
50						0 1 2 3	0 1 2 9	0 10 3 3	0 10 3 5	0 10 3 7	0 10 3 7	0 10 3 9
64							0 0 8 1 7	0 0 8 2 2	0 0 8 2 5	0 0 8 2 7	0 0 8 2 8	0 0 8 2.9
80								0 0 7 1 5	0 0 7 1 7	0 0 7 2 0	0 0 7 2.1	0 0 7 2 2
100									0 0 5 1 1	0 0 5 1 5	0 0 5 1 5	0 0 5 1 7
125										0 0 4 0 8	0 0 4 0 9	0 0 4 1 2
128												
160										0 0 4 0 8	0 0 4 0 9	0 0 4 1 1
												0.0 3 0.7

C=1

N	10	20	30	40	50	60	80	100	120	150	160	200
n	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD
2	27 95	24 95	24 95	23 95	23 95	23 95	23 95	23 95	23 95	22 95	22 95	22 95
4	15 62	12 66	12 66	11 67	11 67	10 67	10 67	10 67	10 67	9 8 67	9 7 67	9.7 68
5	13 51	10 55	8.8 56	8 5 57	8 4 57	8.1 58	7 9 58	7 6 58	7 5 58	7 5 58	7 5 58	7.5 58
8	11 28	7 2 35	6 2 38	5 8 38	5 4 39	5 0 39	4 7 39	4.5 39	4 3 39	4 3 40	4 2 40	4 2 40
10		6.2 30	5 0 30	4 6 31	4 2 32	4 2 32	4.2 32	3.9 33	3 5 33	3 3 33	3 3 33	3.3 33
16		5 6 15	4 2 18	3 8 18	3 4 20	3 0 20	2 9 21	2 6 21	2.5 21	2.3 21	2 3 22	2 2 22
20			4.0 13	3 2 15	2 8 16	2 5 16	2 4 16	2 3 16	2 1 17	2 0 17	2 0 17	2 0 18
25			3 8 9 2	3 1 11	2 5 12	2.2 13	2 0 13	1 8 13	1 7 13	1 6 14	1.6 14	1 6 14
32				3 1 7 4	2 4 8 2	2 1 9 0	1 8 9.9	1 6 10	1 5 10 5	1 4 11	1 3 11	1 3 11
40					2.4 5 9	2.1 6.8	1.6 7.6	1.4 7 8	1.3 8.2	1.2 8.3	1 2 8.4	1.2 8.6
50						1 7 4 6	1.4 5 6	1 2 6 1	1.2 6 4	1.0 65	0 9 6 7	0 9 6 7
64							1 3 3 8	1 1 4 4	1 0 4 7	0 8 5.0	0 8 5 0	0 7 5 2
80								1 1 3.0	1 0 3 4	0 8 3.7	0.7 3 8	0 6 4 0
100									0 9 2 5	0 7 2 8	0 7 2.8	0 6 3 0
125										0 7 1 9	0.7 2 0	0 5 2 2
128												
160										0 7 1 7	0 7 1 9	0 5 2 2
												0.5 1.5

C=2

N	10	20	30	40	50	60	80	100	120	150	160	200
n	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD
4	33 82	28 83	27 84	27 85	27 85	26 85	26 85	26 86	26 86	25 86	25 86	25 86
5	27 69	23 73	21 74	20 74	20 74	20 75	20 75	19 75	19 75	19 75	19 75	19 75
8	22 42	15 49	14 49	13 52	13 52	13 52	12 53	12 53	12 53	11 53	11 53	11 53
10		13 39	11 42	11 42	10 43	10 43	9.6 43	9 2 44	9.1 44	8.9 44	8.9 44	8.7 44
16		11 22	8 6 25	6.9 27	6 8 27	6 4 27	6 0 28	6.0 29	5 9 29	5 9 29	5 7 29	5.5 30
20			7.7 19	6 2 21	5 9 22	5 6 22	5 1 23	4 8 23	4.8 23	4 6 23	4.5 24	4 5 24
25			7 4 13	6 0 16	4 9 17	4 5 17	4 3 18	4 1 18	3 9 18	3 7 18	3.7 19	3 7 19
32				5 5 11	4 8 12	4.3 13	3 6 14	3 4 14	3 2 14	3 0 14 5	3 0 15	2 9 15
40					4 6 8.9	3 9 9.8	3.1 11	2 8 12	2.6 12	2.4 12	2 4 12	2 3 12
50						3 5 6 9	2.8 8 1	2 4 8 4	2.3 8 6	2.1 9 0	2 1 9 3	2 0 9 5
64							2 6 5 7	2 2 6.2	2 0 6 6	1 8 7.1	1.7 7 1	1 6 7 4
80								2 1 4 5	1 8 4 9	1 6 5 4	1 5 5 4	1 4 5 6
100									1 8 3.5	1 4 3 9	1 4 4 0	1 2 4 4
125										1 4 2.8	1 3 2 9	1 1 3 3
128												
160										1 4 2 6	1 3 2 9	1 1 3 2
												1.1 2.3

ANNEXE I

This table gives the AQL and LTPD values associated with certain single sampling plans (Acceptance Number "C", Sample Size "n" and Lot Size "N"). The table has the following features:-

(a) Calculations are based upon the hyper-geometric distribution (exact theory) for lot sizes of 200 or less.

(b) The AQL of a sampling plan is defined as the interpolated Percent Defective for which there is a 0.95 probability of acceptance under the plan. The AQL so defined need not be a realisable Lot Percent Defective for the lot size involved (e.g., 12 percent is not a realisable Percent Defective for a lot size of 20 devices).

(c) The LTPD of a sampling plan is defined as the interpolated Percent Defective for which there is a 0.10 probability of lot acceptance under the plan. The LTPD so defined need not be a realisable Lot Percent Defective for the lot size involved.

(d) The sequence of sample sizes and lot sizes are generated by taking products of preceding numbers in the respective sequences and the numbers 2 and 5.